



## Metrology

### Key Features

- › World-class 200mm 65nm technology node-capable tool set
- › 65nm technology node-capable defect inspection, monitoring and control
- › SPC-controlled and stable equipment with a production CMOS pedigree
- › Full range of metrology for thin film, topography, critical dimension and registration assessment
- › State-of-the-art metallic element control metrology & protocol to ensure the fab remains CMOS-capable for all customers' development efforts
- › Mobile ion monitoring capability to support your development
- › Capacitive-Voltage and Current-Voltage monitoring capability for state-of-the-art dielectric monitoring
- › A full suite of electrical test capabilities for monitoring parametrics for both our baseline and your line

SVTC Technologies is an independent semiconductor process-development foundry that enables the development and commercialization of innovative semiconductor-based technologies and products in an accelerated, cost-effective and IP-secure way.

SVTC's metrology tools, from leading equipment manufacturers, offer advanced capabilities that enable you to monitor, measure and inspect your development processes. We provide a broad spectrum of metrology capabilities at both our San Jose, California, and Austin, Texas, facilities.



## Metrology

Capability	Tools	FE/BE	Location
Epi doping	Prometrix 4 pt probe	FE	San Jose
Dielectric Monitor (mobile ion, EDT, trap density, charge)	KLA Quantox	FE	San Jose
Implanter Monitor	Prometrix	FE	San Jose
Thin Film Thickness and Composition	KLA ASET F5x, Thermawave Optiprobe	FE/BE	San Jose
Step Height	Tencor P22	FE/BE	San Jose
Stress	Flexus	FE/BE	San Jose
Dopant & Contamination Concentration	Biorad - FTIR	FE/BE	San Jose
SEM Critical Dimension Measurements	AMAT Verity CD SEM, AMAT VeraSEM	FE/BE	San Jose
Overlay	KLA ArcherAIM	FE/BE	San Jose
Blank Wafer Defect inspection to > 65 nm	KLA SP1 TBI	FE/BE	San Jose
Pattern Wafer Defect Inspection to > 60 nm	KLA 2360	FE/BE	San Jose
Epi / SiGe thickness	Biorad FTIR	FE/BE	San Jose
Contamination	Technos TXRF620	FE/BE	San Jose
Top View Scanning Electron Inspection & Micrographs	AMAT G2 Full Wafer Inspection SEM	FE/BE	San Jose
Metal Thickness	Prometrix	BE	San Jose
Ellipsometer Dielectric Thickness, N & K Values	JA Woollam VU-301	FE	Austin
EOT measurement - Gate Monitor	KLA-Tencor Quantox-300	FE	Austin
Ellipsometry - Film Thk w UV/Deuterium Source w Desorber	Thermawave OP5240 Opti-Probe	FE	Austin
Dark Field Wafer Defect Inspection	AMAT Complux	FE/BE	Austin
Four Point Probe contact Resistivity	Four Dimensions 300	FE/BE	Austin
Four Point Probe contact Resistivity	Prometrix 4PT probe	FE/BE	Austin
Inspection Scope, (150X)	Kinetek DR-300C	FE/BE	Austin
Defview Review & UV Inspec. scope, (x250)	Olympus, FR3200	FE/BE	Austin
Automated Particle Unpat. Surf. Insp.	KLA-Tencor Surfscan 6420 or 6220	FE/BE	Austin
Film Stress & Wafer Bow	KLA-Tencor Flexus 5400	FE/BE	Austin
Film Stress & Wafer Bow	Frontier Semiconductor FSM 9000-TC	FE/BE	Austin
Dopant and Contamination Concentration	Nicolet Magna 550 Series II	FE/BE	Austin
Film Thickness Measurement- Reflectometry	KLA-Tencor UV1050	FE/BE	Austin
Film Thickness Measurement- Reflectometry	Prometrix FT530	FE/BE	Austin
Inductively Coupled Plasma Mass Spec	Agilent Technologies 4500	FE/BE	Austin
Texture Measurement - Laser based	Veeco TMS-3000W	FE/BE	Austin
Profiler/Atomic Force Micro. - Tapping Mode with Silicon Tip	Veeco - Digital Instruments VX310 AFM	FE/BE	Austin
Wafer Flatness	ADE 9700	FE/BE	Austin
Total Reflect X-Ray Fluor. Spect.	TECHNOS (PHILLIPS) TREX630	FE/BE	Austin
Overlay inspection	KLA-Tencor 5100-03 Auto Misreg Sys	FE/BE	Austin
SEM Top-Down CD, Etch Depth & Profile Angle w Tilt	AMAT CD-SEM Metrology Sys 3D or AMAT Verity SEM	FE/BE	Austin
Metal Film T- Opto-acoustic, Automated	Phillips Impulse 300B	BE	Austin
X-Ray Refl./X-Ray Flor. Thin Film measurement	Jordan Valley JVX 5200T XRR/XRF TF Meas.	BE	Austin

## FACT SHEET



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